2.5V Drive Nch+SBD MOSFET **US6U37**

Structure

Silicon N-channel MOSFET / Schottky barrier diode

● Features

- 1) Nch MOSFET and schottky barrier diode are put in TUMT6 package.
- 2) High-speed switching, Low On-resistance.
- 3) Low voltage drive (2.5V drive).
- 4) Built-in Low VF schottky barrier diode.

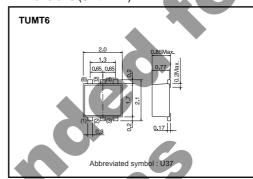
Applications

Switching

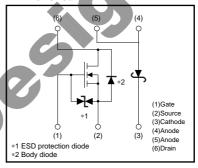
Package specifications

	Package	Taping		
Type	Code	TR		
	Basic ordering unit (pieces)	3000		
US6U37		(0)		

●Dimensions (Unit: mm)



●Inner circuit



● Absolute maximum ratings (Ta=25°C)

<MOSFET>

Parameter	Symbol	Limits	Unit	
Drain-source voltage		V _{DSS}	30	V
Gate-source voltage		Vgss	±12	V
Drain current	Continuous	lo	±1.5	Α
	Pulsed	I _{DP} *1	±6.0	Α
Source current	Continuous	Is	0.6	A
(Body diode)	Pulsed	I _{SP} *1	6.0	Α
Channel temperature		Tch	150	°C
Power dissipation		P _D *2	0.7	W / ELEMENT

¹ Pw≤10μs, Duty cycle≤1% 2 Mounted on a ceramic board

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NDI2				
Parameter	Symbol	Limits	Unit	
Repetitive peak reverse voltage	V _{RM}	25	V	
Reverse voltage	VR	20	V	
Forward current	lF	0.7	Α	
Forward current surge peak	IFSM *1	10	A	
Junction temperature	Tj	150	°C	
Power dissipation	P _D *2	0.5	W / ELEMENT	

^{*1 60}Hz • 1cycle *2 Mounted on ceramic board

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Parameter	Symbol	Limits	Unit	
Power dissipation	P _D *1	1.0	W / TOTAL	
Range of storage temperature	Tstg	-55 to +150	°C	

^{*1} Mounted on a ceramic board

●Electrical characteristics (Ta=25°C)

<MOSFET>

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Gate-source leakage	Igss	_	_	±10	μΑ	V _{GS} =±12V, V _{DS} =0V
Drain-source breakdown voltage	V(BR) DSS	30	ı	_	V	ID= 1mA, VGS=0V
Zero gate voltage drain current	I _{DSS}	_	_	1	μΑ	V _{DS} = 30V, V _{GS} =0V
Gate threshold voltage	V _{GS (th)}	0.5	_	1.5	V	V _{DS} = 10V, I _D = 1mA
Otation Indiana and a state		_	170	240	mΩ	I _D = 1.5A, V _G s= 4.5V
Static drain-source on-state resistance	R _{DS (on)} *	_	180	250	mΩ	I _D = 1.5A, V _G S= 4V
resistance		_	240	340	mΩ	ID= 1.5A, VGS= 2.5V
Forward transfer admittance	Y _{fs} *	1.5	-	_	S	V _{DS} = 10V, I _D = 1.5A
Input capacitance	Ciss	_	80	_	pF	V _{DS} = 10V
Output capacitance	Coss	_	14	_	pF	V _{GS} =0V
Reverse transfer capacitance	Crss	_	12	_	pF	f=1MHz
Turn-on delay time	t _{d (on)} *	_	7	- ,	ns	Vdd≒ 15V
Rise time	tr *	_	9		ns	Ib= 0.75A Vgs= 4.5V
Turn-off delay time	t _{d (off)} *	_	15	_	ns	$R_{L} = 20\Omega$
Fall time	t _f *	_	6	<u> </u>	ns	R _G =10Ω
Total gate charge	Qg *		1.6	2.2	nC	V _{DD} = 15V, V _{GS} = 4.5V
Gate-source charge	Q _{gs} *	- /	0.5	—	nC	I _D = 1.5A
Gate-drain charge	Q _{gd} *	4	0.3	-	nC	$R_L = 10\Omega$, $R_G = 10\Omega$

*Pulsed

<Body diode characteristics (Source-drain)>

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Forward voltage	Vsp	_		1.2	V	I _S = 0.6A, V _{GS} =0V

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Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Forward voltage	VF	<i>F</i>	, -	0.49	V	I _F = 0.7A
Reverse current	l _R		_	200	μΑ	V _R = 20V

Electrical characteristics curves

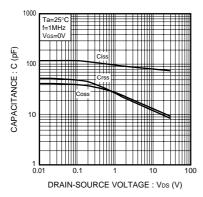


Fig.1 Typical Capacitance vs. Drain-Source Voltage

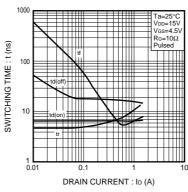


Fig.2 Switching Characteristics

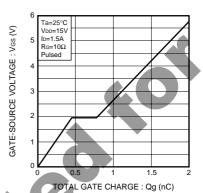


Fig.3 Dynamic Input Characteristics

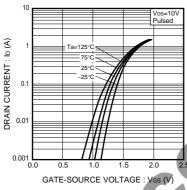


Fig.4 Typical Transfer Characteristics

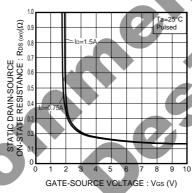


Fig.5 Static Drain-Source On-State Resistance vs. Gate source Voltage

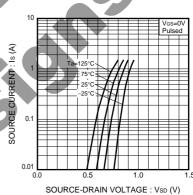


Fig.6 Source Current vs. Source-Drain Voltage

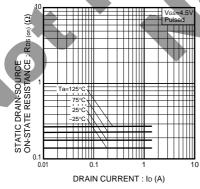


Fig.7 Static Drain-Source On-State Resistance vs. Drain Current (I)

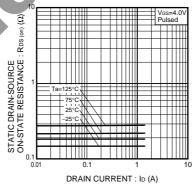


Fig.8 Static Drain-Source On-State Resistance vs. Drain Current (II)

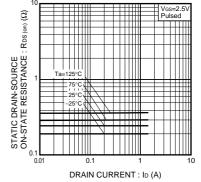
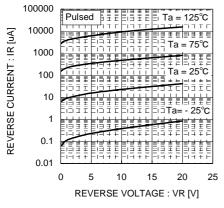


Fig.9 Static Drain-Source On-State Resistance vs. Drain Current (III)



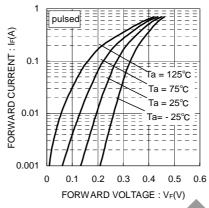


Fig.10 Reverse Current vs. Reverse

Fig.11 Forward Current vs. Forward Voltage

Measurement circuit

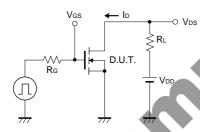


Fig.12 Switching Time Test Circuit

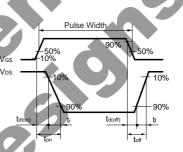


Fig.13 Switching Time Waveforms

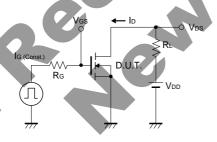


Fig.14 Gate Charge Measurement Circuit

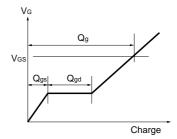


Fig.15 Gate Charge Waveform

●Notice

- 1. SBD has a large reverse leak current compared to other type of diode. Therefore; it would raise a junction temperature, and increase a reverse power loss. Further rise of inside temperature would cause a thermal runaway.
 This built-in SBD has low V_F characteristics and therefore, higher leak current. Please consider enough the surrounding temperature, generating heat of MOSFET and the reverse current.
- 2. This product might cause chip aging and breakdown under the large electrified environment. Please consider to design ESD protection circuit.

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